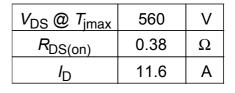


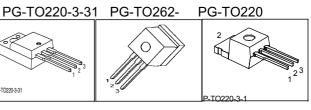
#### **Cool MOS™ Power Transistor**

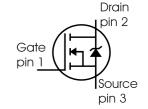
#### **Feature**

- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- PG-TO-220-3-31;-3-111: Fully isolated package (2500 VAC; 1 minute)
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>0)</sup> for target applications

Туре	Package	Ordering Code	Marking
SPP12N50C3	PG-TO220	Q67040-S4579	12N50C3
SPI12N50C3	PG-TO262	Q67040-S4578	12N50C3
SPA12N50C3	PG-TO220FP	SP000216322	12N50C3







## **Maximum Ratings**

Parameter	Symbol	Va	Unit	
		SPP_I	SPA	
Continuous drain current	$I_{D}$			Α
$T_{\rm C}$ = 25 °C		11.6	11.6 <sup>1)</sup>	
T <sub>C</sub> = 100 °C		7	71)	
Pulsed drain current, $t_p$ limited by $T_{jmax}$	I <sub>D puls</sub>	34.8	34.8	Α
Avalanche energy, single pulse	E <sub>AS</sub>	340	340	mJ
I <sub>D</sub> =5.5A, V <sub>DD</sub> =50V				
Avalanche energy, repetitive $t_{AR}$ limited by $T_{jmax}^{2}$	E <sub>AR</sub>	0.6	0.6	
I <sub>D</sub> =11.6A, V <sub>DD</sub> =50V				
Avalanche current, repetitive $t_{AR}$ limited by $T_{jmax}$	I <sub>AR</sub>	11.6	11.6	Α
Gate source voltage	V <sub>GS</sub>	±20	±20	V
Gate source voltage AC (f >1Hz)	$V_{\rm GS}$	±30	±30	
Power dissipation, $T_C = 25^{\circ}C$	P <sub>tot</sub>	125	33	W
Operating and storage temperature	$T_{j}$ , $T_{stg}$	-55	.+150	°C
Reverse diode dv/dt 7)	dv/dt	1	5	V/ns



**Maximum Ratings** 

Parameter	Symbol	Value	Unit
Drain Source voltage slope	dv/dt	50	V/ns
$V_{\rm DS}$ = 400 V, $I_{\rm D}$ = 11.6 A, $T_{\rm j}$ = 125 °C			

### **Thermal Characteristics**

Parameter		Values		Unit	
		min.	typ.	max.	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	1	K/W
Thermal resistance, junction - case, FullPAK	R <sub>thJC_FP</sub>	-	-	3.8	
Thermal resistance, junction - ambient, leaded	$R_{thJA}$	-	-	62	
Thermal resistance, junction - ambient, FullPAK	R <sub>thJA_FP</sub>	-	-	80	
SMD version, device on PCB:	R <sub>thJA</sub>				
@ min. footprint		-	-	62	
@ 6 cm <sup>2</sup> cooling area <sup>3)</sup>		-	35	-	
Soldering temperature, wavesoldering	T <sub>sold</sub>	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s <sup>4)</sup>					

**Electrical Characteristics**, at  $T_j$ =25°C unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =0.25mA	500	-	-	V
Drain-Source avalanche	V <sub>(BR)DS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =11.6A	-	600	-	
breakdown voltage						
Gate threshold voltage	V <sub>GS(th)</sub>	<i>I</i> <sub>D</sub> =500μA, <i>V</i> <sub>GS</sub> =V <sub>DS</sub>	2.1	3	3.9	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =500V, V <sub>GS</sub> =0V,				μA
		<i>T</i> <sub>j</sub> =25°C	-	0.1	1	
		<i>T</i> <sub>j</sub> =150°C	-	-	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	<i>V</i> <sub>GS</sub> =10V, <i>I</i> <sub>D</sub> =7A				Ω
		<i>T</i> <sub>j</sub> =25°C	-	0.34	0.38	
		<i>T</i> <sub>j</sub> =150°C	-	0.92		
Gate input resistance	R <sub>G</sub>	f=1MHz, open drain	-	1.4	-	



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Characteristics				•		•
Transconductance	$g_{fs}$	$V_{\rm DS} \ge 2*I_{\rm D}*R_{\rm DS(on)max}$ , $I_{\rm D}=7A$	-	8	-	S
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V,	-	1200	-	pF
Output capacitance	Coss	<i>f</i> =1MHz	-	400	-	
Reverse transfer capacitance	$C_{rss}$		-	30	-	
Effective output capacitance,5)	C <sub>o(er)</sub>	V <sub>GS</sub> =0V,	-	45	-	
energy related		V <sub>DS</sub> =0V to 400V				
Effective output capacitance,6)	C <sub>o(tr)</sub>		-	92	-	
time related						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =380V, V <sub>GS</sub> =0/10V,	-	10	-	ns
Rise time	t <sub>r</sub>	I <sub>D</sub> =11.6A, R <sub>G</sub> =6.8Ω	-	8	-	
Turn-off delay time	t <sub>d(off)</sub>		-	45	-	
Fall time	<i>t</i> f		-	8	-	
Gate Charge Characteristics		•		•		•

Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =400V, I <sub>D</sub> =11.6A	-	5	-	nC
Gate to drain charge	$Q_{gd}$		-	26	-	
Gate charge total	Qg	V <sub>DD</sub> =400V, I <sub>D</sub> =11.6A,	-	49	-	
		V <sub>GS</sub> =0 to 10V				
Gate plateau voltage	V <sub>(plateau)</sub>	V <sub>DD</sub> =400V, I <sub>D</sub> =11.6A	-	5	-	V

<sup>&</sup>lt;sup>0</sup>J-STD20 and JESD22

Identical low-side and high-side switch.

<sup>&</sup>lt;sup>1</sup>Limited only by maximum temperature

<sup>&</sup>lt;sup>2</sup>Repetitve avalanche causes additional power losses that can be calculated as  $P_{AV} = E_{AR} * f$ .

<sup>&</sup>lt;sup>3</sup>Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

<sup>&</sup>lt;sup>4</sup>Soldering temperature for TO-263: 220°C, reflow

 $<sup>^5</sup>C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

 $<sup>^6</sup>C_{\rm o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 80%  $V_{\rm DSS}$ .

 $<sup>7</sup>I_{SD} <= I_D$ , di/dt <= 400A/us,  $V_{DClink} = 400V$ ,  $V_{peak} < V_{BR, DSS}$ ,  $T_j < T_{j,max}$ .

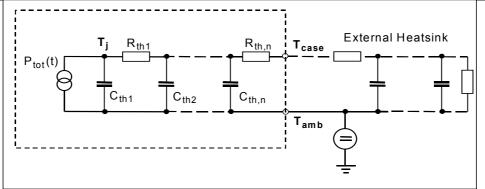


### **Electrical Characteristics**

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Inverse diode continuous	IS	T <sub>C</sub> =25°C	-	-	11.6	Α
forward current						
Inverse diode direct current,	/ <sub>SM</sub>		_	-	34.8	
pulsed						
Inverse diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>F</sub> =I <sub>S</sub>	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =400V, I <sub>F</sub> =I <sub>S</sub> ,	-	380	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i</i> <sub>F</sub> /d <i>t</i> =100A/μs	-	5.5	-	μC
Peak reverse recovery current	<i>I</i> <sub>rrm</sub>		_	38	-	Α
Peak rate of fall of reverse	di <sub>rr</sub> /dt	<i>T</i> <sub>j</sub> =25°C	-	1100	-	A/µs
recovery current						

## **Typical Transient Thermal Characteristics**

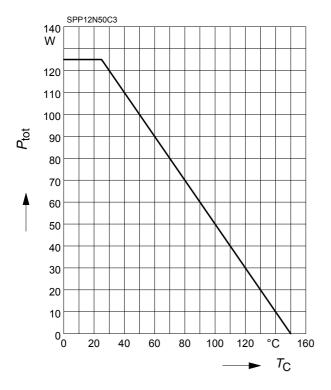
Symbol	Va	lue	Unit	Symbol	Va	lue	Unit
	SPP_I	SPA			SPP_I	SPA	
R <sub>th1</sub>	0.015	0.15	K/W	C <sub>th1</sub>	0.0001878	0.0001878	Ws/K
R <sub>th2</sub>	0.03	0.03		C <sub>th2</sub>	0.0007106	0.0007106	
R <sub>th3</sub>	0.056	0.056		C <sub>th3</sub>	0.000988	0.000988	
R <sub>th4</sub>	0.197	0.194		C <sub>th4</sub>	0.002791	0.002791	
R <sub>th5</sub>	0.216	0.413		C <sub>th5</sub>	0.007285	0.007401	
R <sub>th6</sub>	0.083	2.522		C <sub>th6</sub>	0.063	0.412	





#### 1 Power dissipation

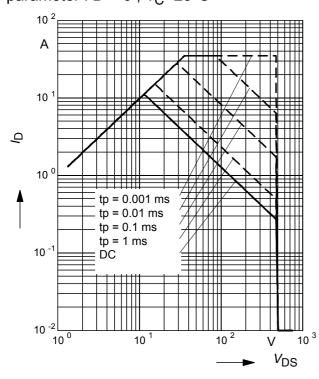
$$P_{\text{tot}} = f(T_{\text{C}})$$



### 3 Safe operating area

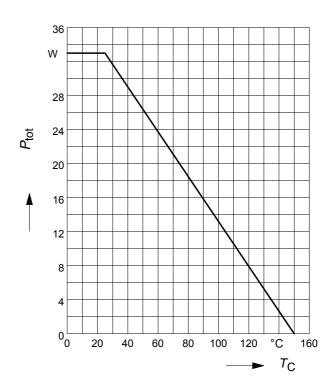
$$I_{\rm D} = f(V_{\rm DS})$$

parameter : D = 0 ,  $T_C = 25^{\circ}C$ 



## 2 Power dissipation FullPAK

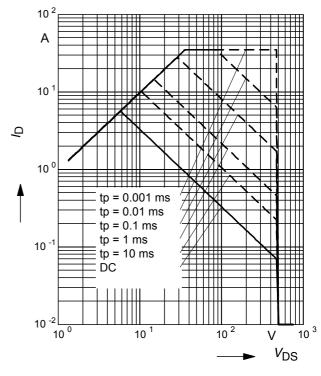
$$P_{\text{tot}} = f(T_{\text{C}})$$



### 4 Safe operating area FullPAK

$$I_{\rm D} = f(V_{\rm DS})$$

parameter: D = 0,  $T_C = 25$ °C

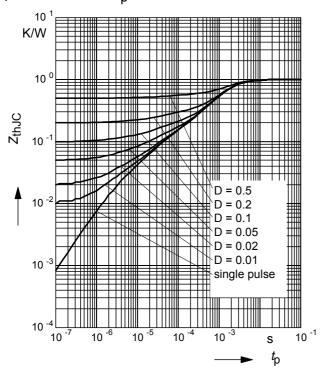




## 5 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

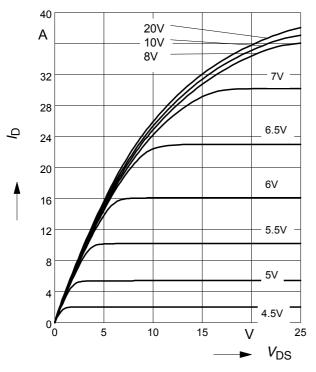
parameter:  $D = t_D/T$ 



## 7 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=25^{\circ}C$ 

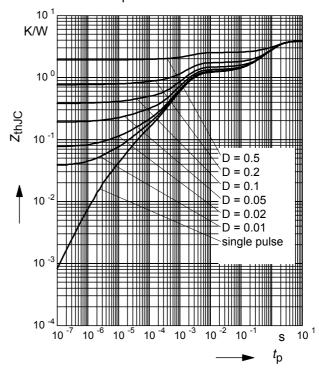
parameter:  $t_p$  = 10  $\mu$ s,  $V_{GS}$ 



## 6 Transient thermal impedance FullPAK

$$Z_{\mathsf{thJC}} = f\left(t_{\mathsf{p}}\right)$$

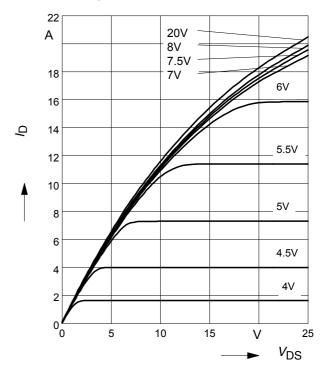
parameter:  $D = t_p/t$ 



## 8 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=150^{\circ}C$ 

parameter:  $t_p$  = 10  $\mu$ s,  $V_{GS}$ 

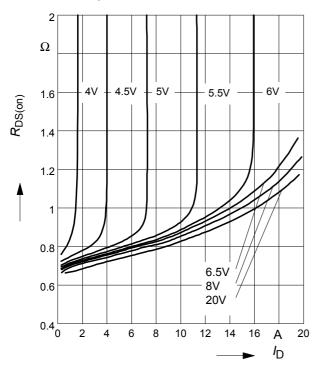




## 9 Typ. drain-source on resistance

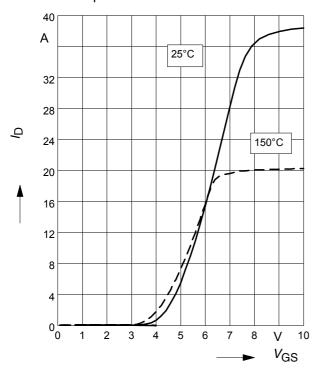
 $R_{DS(on)} = f(I_D)$ 

parameter:  $T_j$ =150°C,  $V_{GS}$ 



### 11 Typ. transfer characteristics

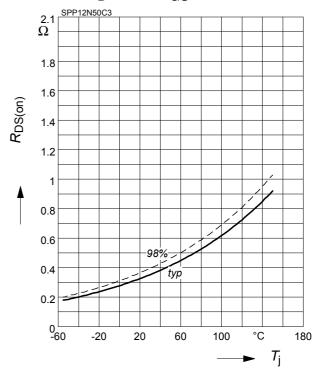
 $I_{\rm D}$ =  $f(V_{\rm GS})$ ;  $V_{\rm DS}$  $\geq 2 \times I_{\rm D} \times R_{\rm DS(on)max}$  parameter:  $t_{\rm p}$  = 10  $\mu$ s



#### 10 Drain-source on-state resistance

 $R_{\text{DS(on)}} = f(T_{j})$ 

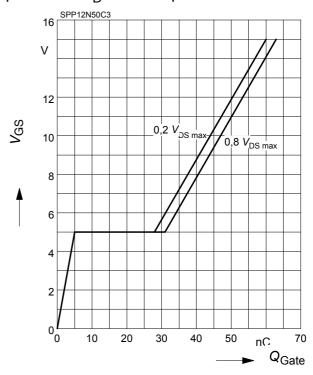
parameter :  $I_D$  = 7 A,  $V_{GS}$  = 10 V



### 12 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$ 

parameter:  $I_D$  = 11.6 A pulsed

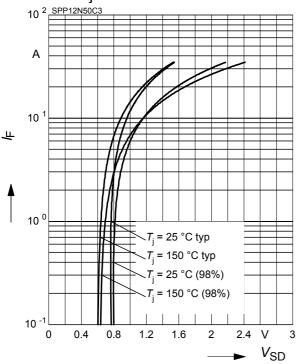




## 13 Forward characteristics of body diode

$$I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$$

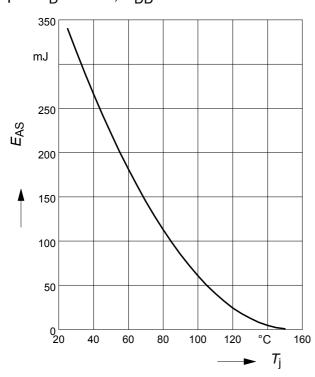
parameter:  $T_i$ ,  $t_p = 10 \mu s$ 



## 15 Avalanche energy

$$E_{AS} = f(T_i)$$

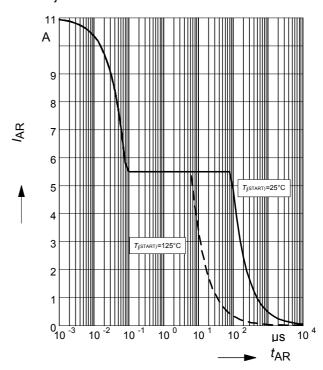
par.:  $I_D = 5.5 \text{ A}, V_{DD} = 50 \text{ V}$ 



14 Avalanche SOA

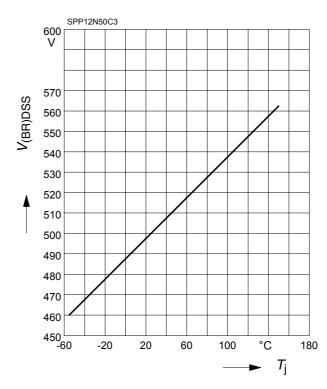
 $I_{AR} = f(t_{AR})$ 

par.: *T*<sub>i</sub> ≤ 150 °C



### 16 Drain-source breakdown voltage

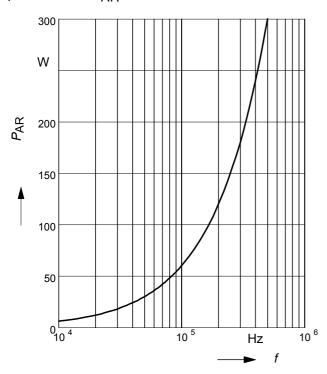
$$V_{(BR)DSS} = f(T_j)$$



## 17 Avalanche power losses

 $P_{AR} = f(f)$ 

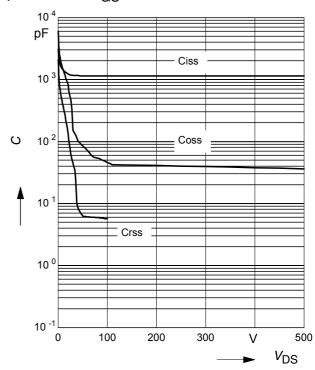
parameter: E<sub>AR</sub>=0.6mJ



## 18 Typ. capacitances

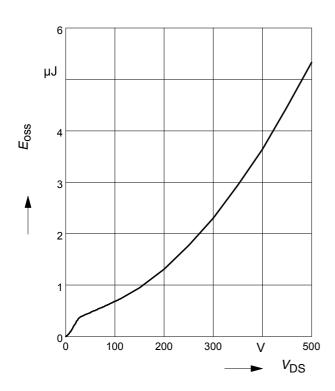
 $C = f(V_{DS})$ 

parameter: V<sub>GS</sub>=0V, f=1 MHz



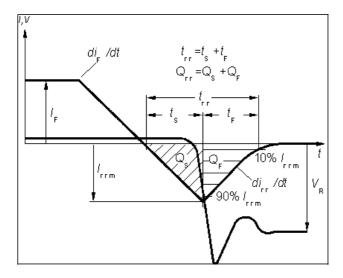
# 19 Typ. $C_{\rm OSS}$ stored energy

 $E_{\rm oss} = f(V_{\rm DS})$ 



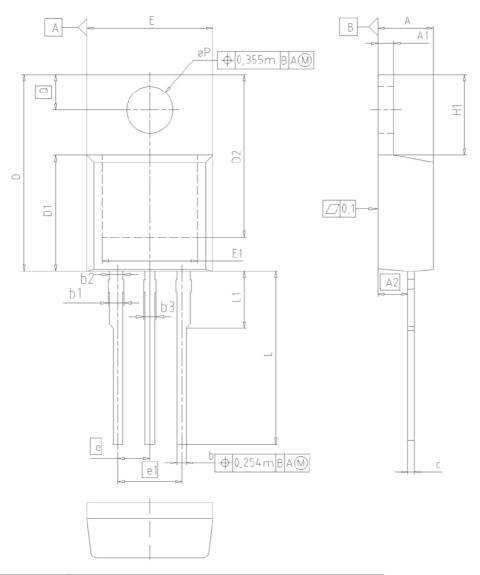


## Definition of diodes switching characteristics





## PG-TO-220-3-1, PG-TO220-3-21

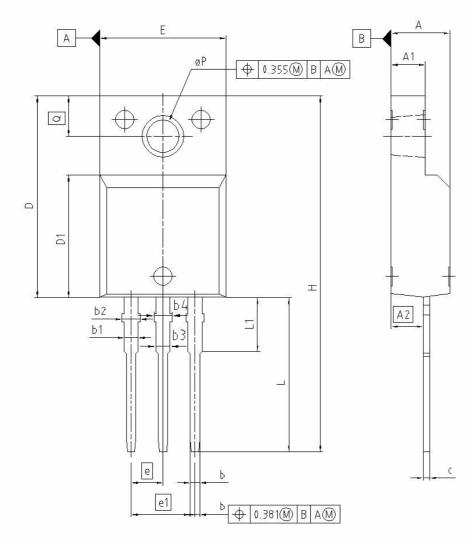


DIM	MILLIM	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.5	54	0.1	00
e1	5.0	08	0.2	200
N		3	;	3
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

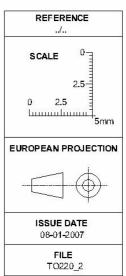
DOCUMEN Z8B0000	
SCALE	2.5
0 2.5	5mm
EUROPEAN P	ROJECTION
ISSUE D	DATE
23-08-2	2007



## PG-TO220-3-31/3-111 Fully isolated package (2500VAC; 1 minute)

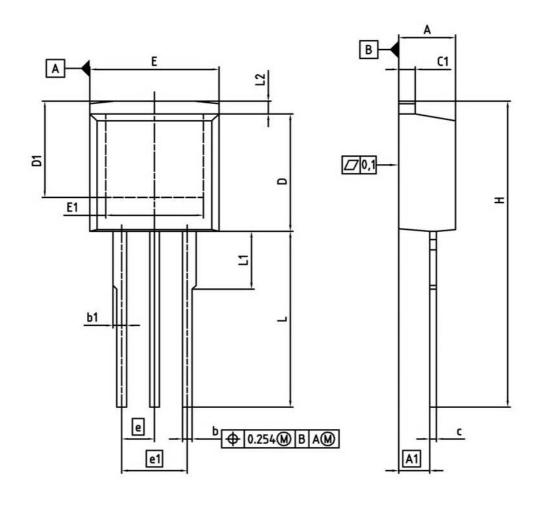


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.55	4.85	0.179	0.191
A1	2.55	2.85	0.100	0.112
A2	2.42	2.72	0.095	0.107
b	0.65	0.85	0.026	0.033
b1	0.95	1.33	0.037	0.052
b2	0.95	1.51	0.037	0.059
b3	0.65	1.33	0.026	0.052
b4	0.65	1.51	0.026	0.059
C	0.40	0.63	0.016	0.025
D	15.85	16.15	0.624	0.636
D1	9.53	9.83	0.375	0.387
E	10.35	10.65	0.407	0.419
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
Н	29.45	29.75	1.159	1.171
L	13.45	13.75	0.530	0.541
L1	3.15	3.45	0.124	0.136
øΡ	2.95	3.20	0.116	0.126
Q	3.15	3.50	0.124	0.138

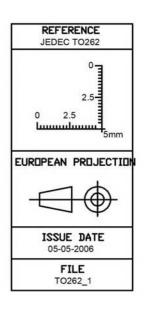




PG-TO262-3-1, PG-TO262-3-21 (I<sup>2</sup>-PAK)



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	2.150	2.718	0.085	0.107
b	0.650	0.864	0.026	0.034
b1	0.635	1.400	0.025	0.055
С	0.330	0.600	0.013	0.024
c1	1.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	6.900		0.272	-
Ε	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
6	2.540		0.100	
e1	5.080		0.200	
N	3		3	
L	13.000	14.000	0.512	0.551
L1	250	4.800	-	0.189
L2		1.727		0.068





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